

FIG.1

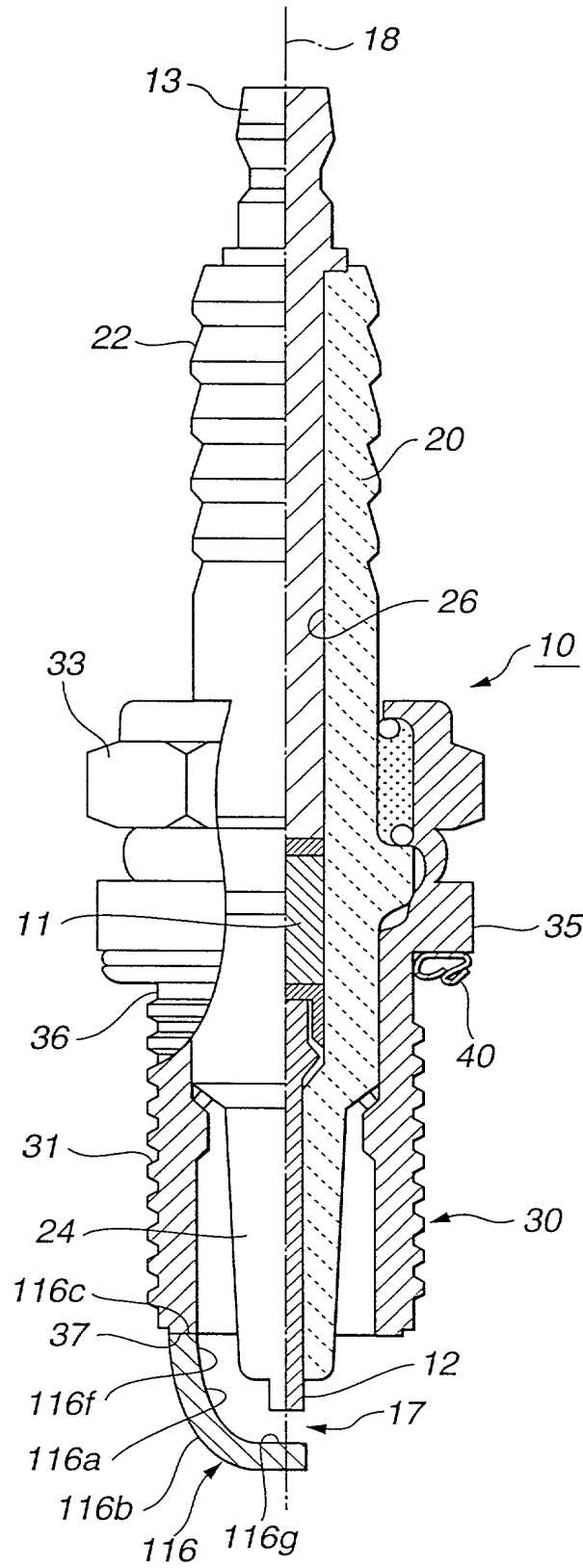


FIG.2A

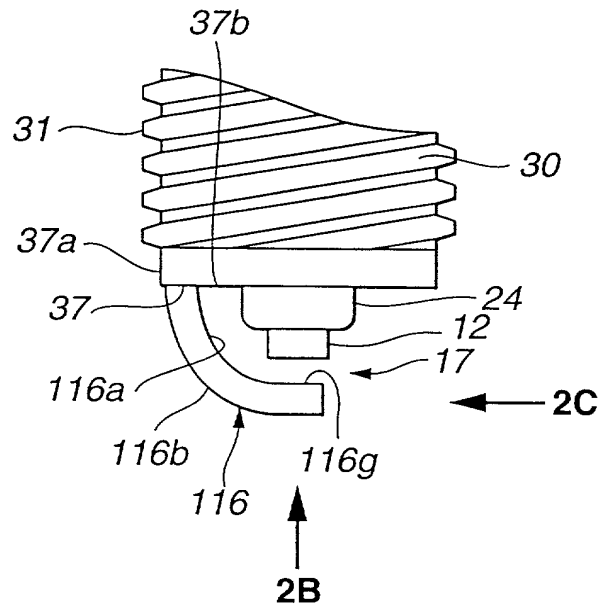


FIG.2B

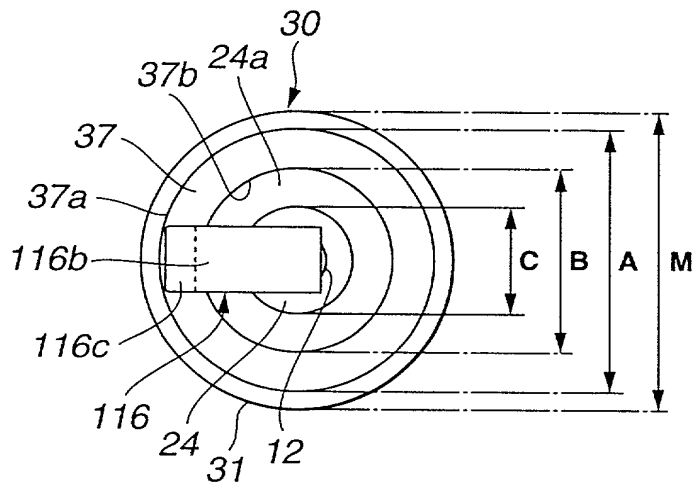


FIG.2C

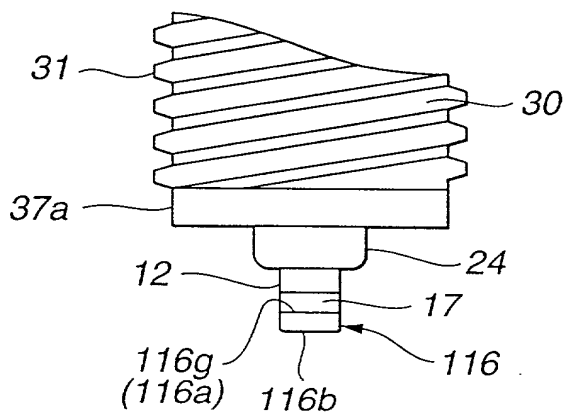


FIG.3A

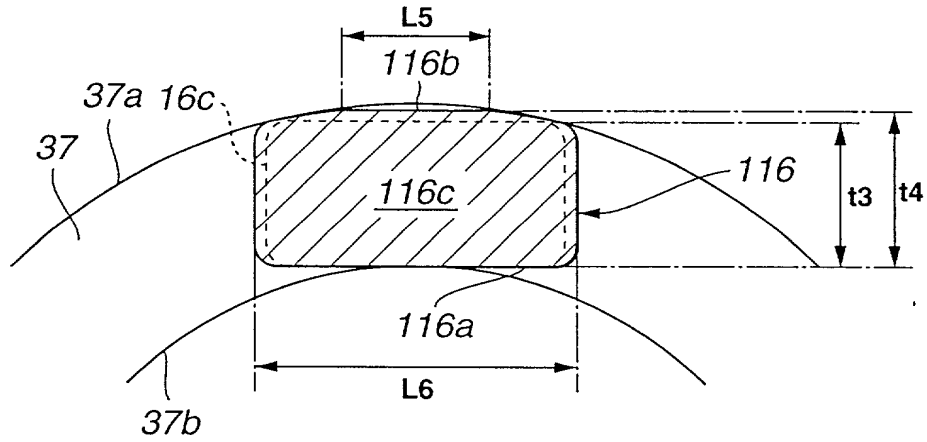


FIG.3B

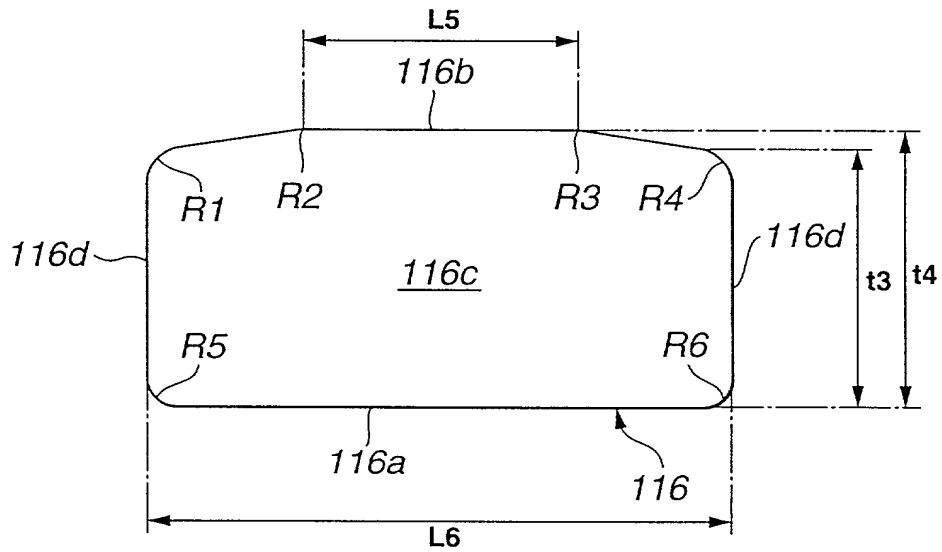


FIG.4

DURABILITY TEST RESULT

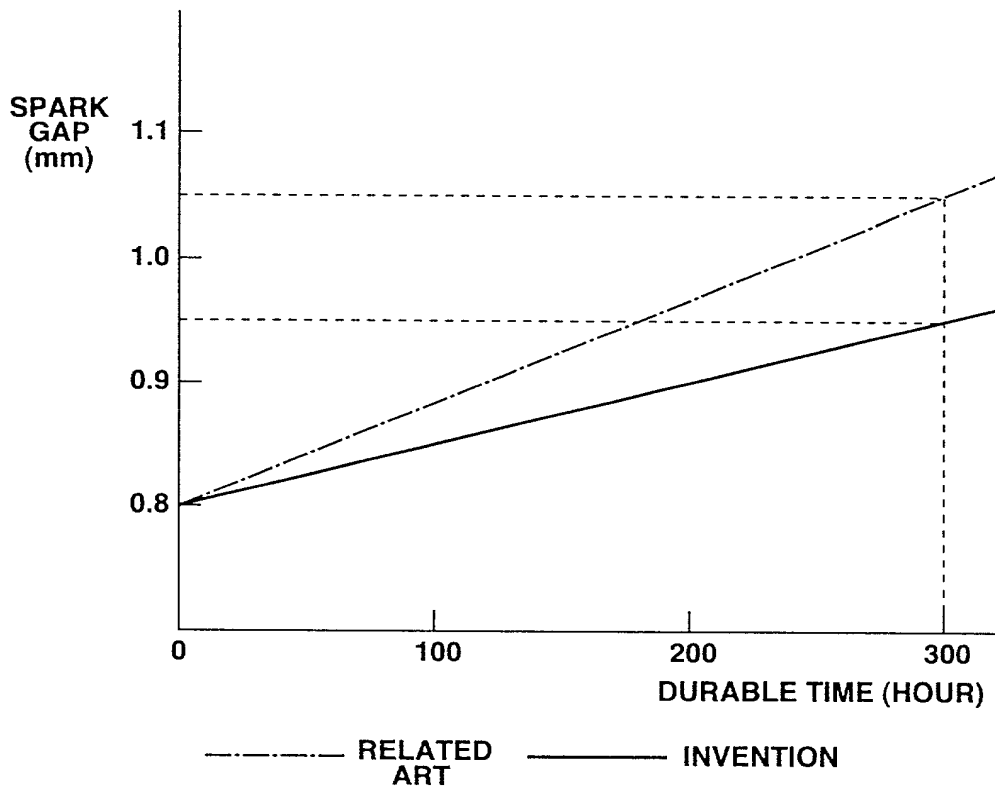


FIG.5

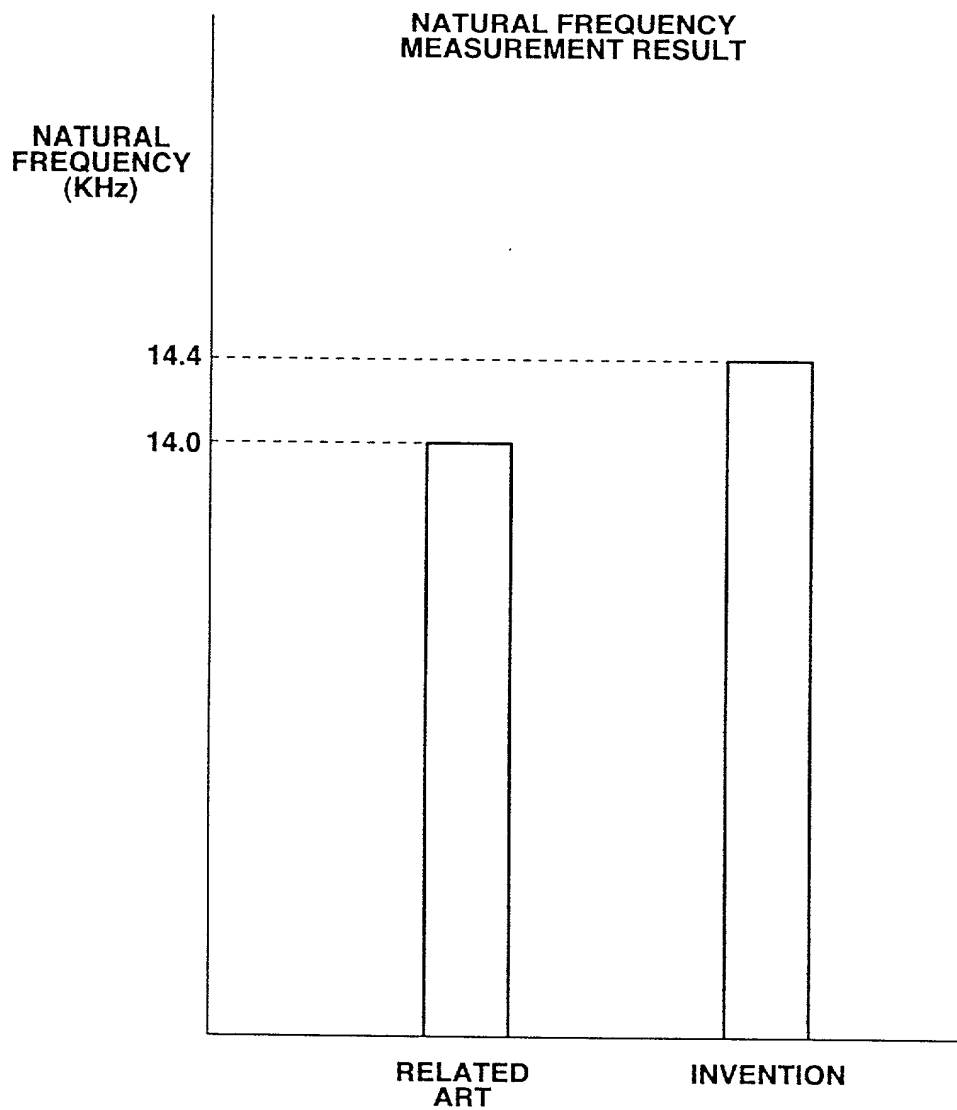


FIG.6

**SIDEWAY JUMPING
 OCCURRENCE TEST RESULT**

		METALLIC SHELL INNER DIAMETER B	INSULATOR FRONT END PORTION DIAMETER C	CLEARANCE D	SIDEWAY JUMPING OCCURRENCE VOLTAGE (BY COMPARISON WITH RELATED ART)
RELATED ART	t1=1.3 L1=2.7	7.20	4.30	1.45	AS USUAL
UNMODIFIED	t2=1.4 L2=2.9	6.94	4.30	1.32	-1.3kV
INVENTION	t4=1.4 L6=2.9 L5=1.4	7.20	4.30	1.45	±0.0kV

FIG.7A

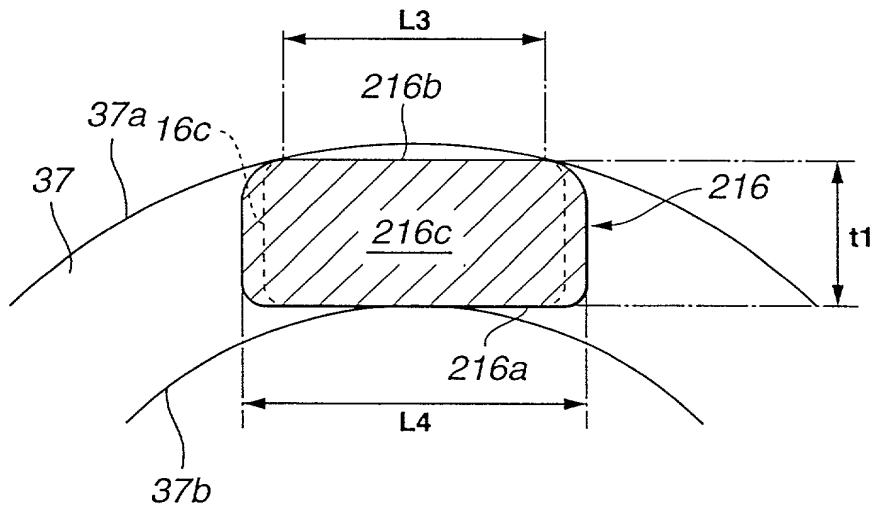


FIG.7B

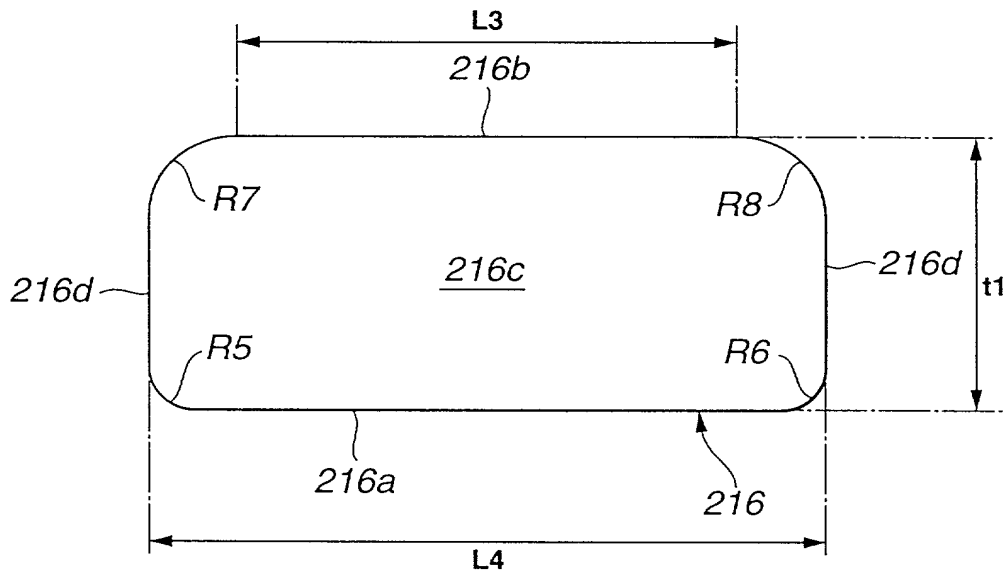


FIG.8A

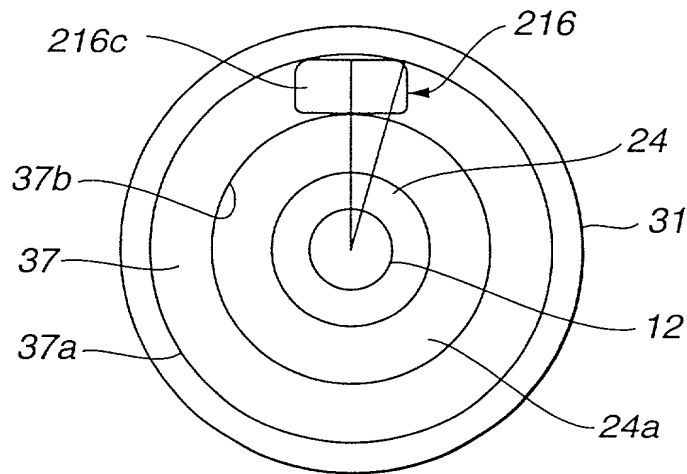


FIG.8B

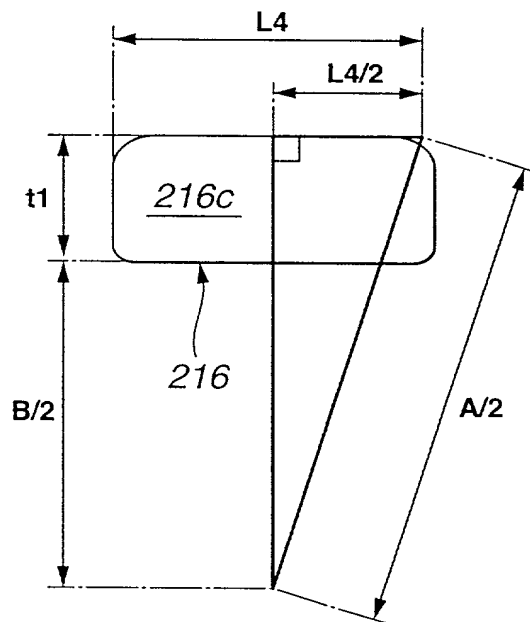


FIG.9A

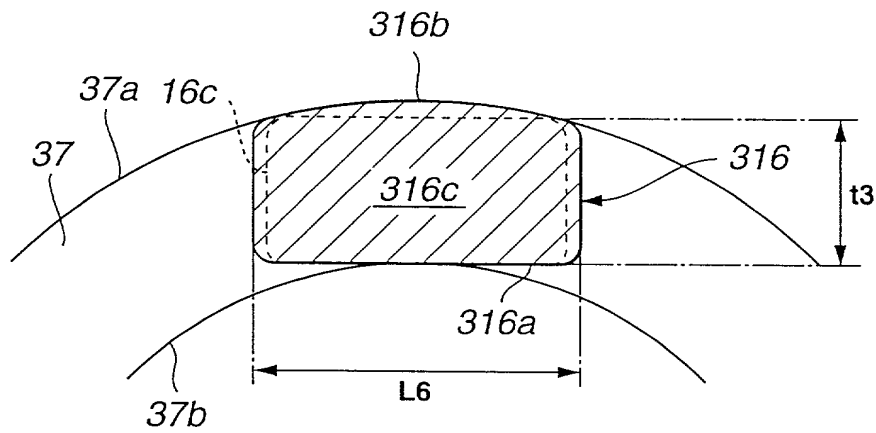


FIG.9B

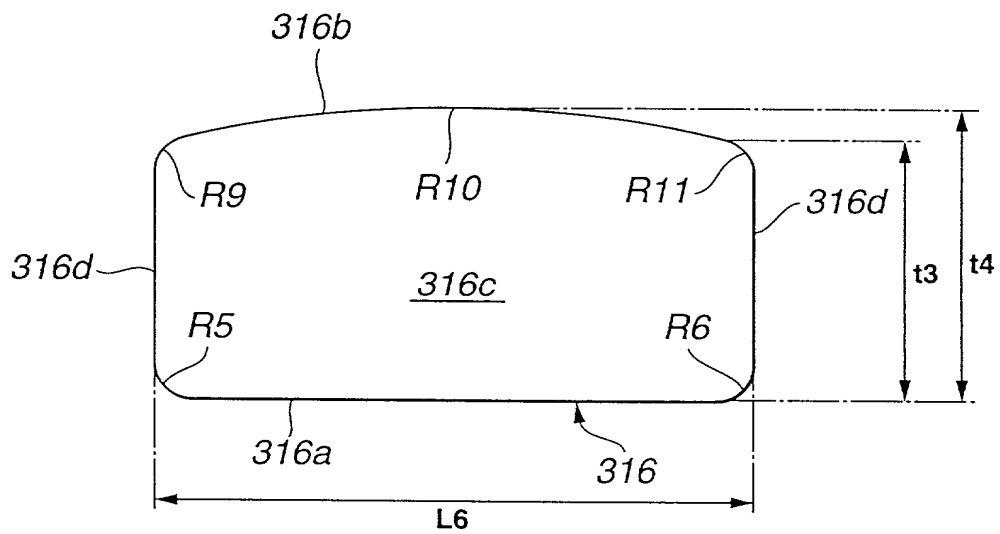


FIG.10A

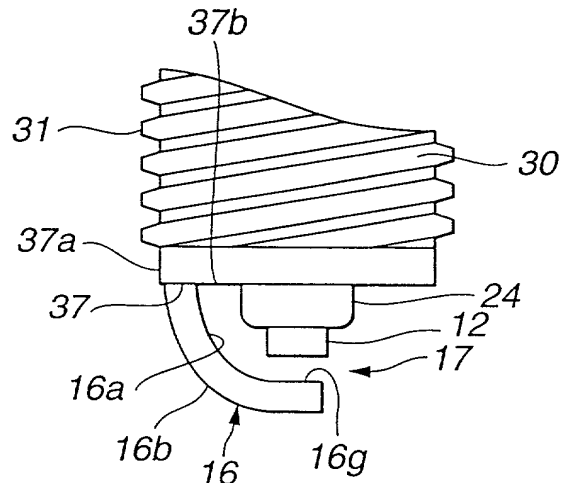


FIG.10B

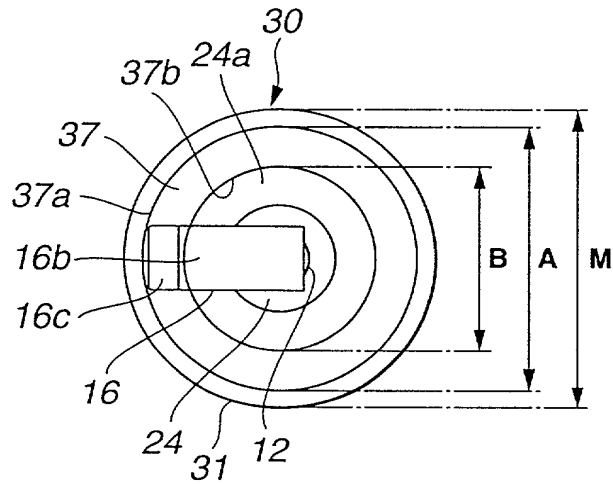


FIG.10C

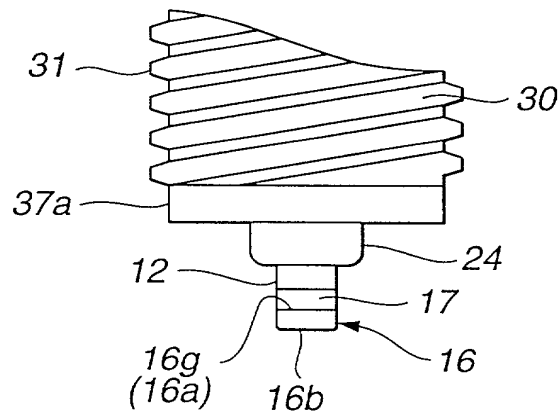


FIG.11A

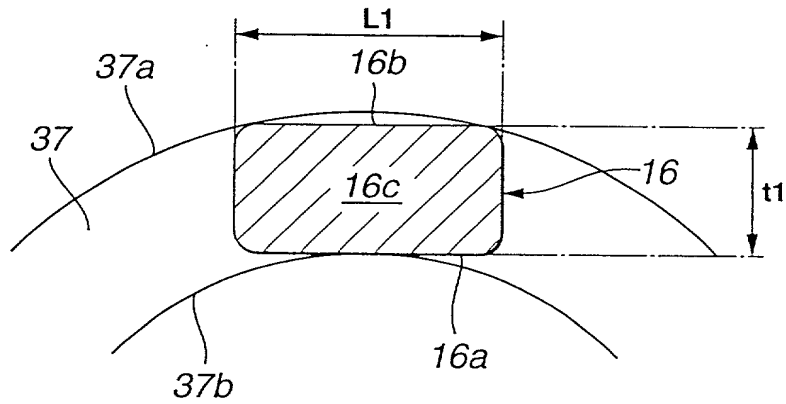


FIG.11B

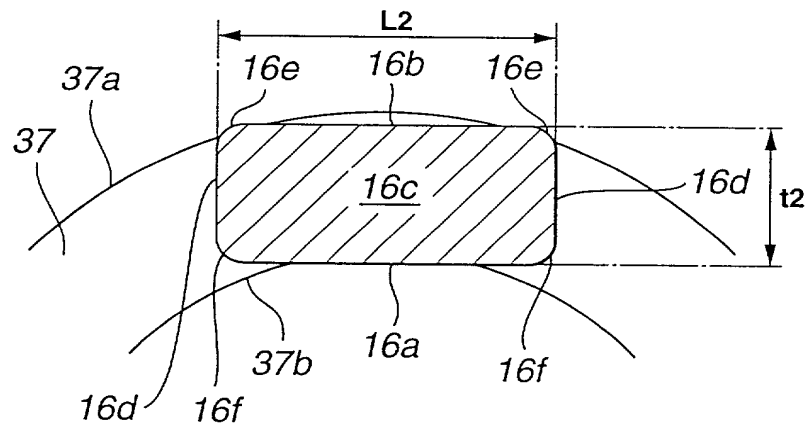


FIG.11C

